2. The RF probe of claim 1, wherein the conductive return is a ground return.

3. The RF probe of claim 1, wherein the termination is a resistor.

4. (Amended) The RF probe of claim 3, wherein the probe conductor is formed within a coaxial conductor and the termination is approximately 50 ohms.

5. The RF probe of claim 1, wherein the termination is a semiconductor device.

6. The RF probe of claim 5, wherein the termination is a diode.

7. (Amended) An RF probe, comprising:

a conductive return;

a probe conductor within an insulator, the insulator having a contact surface; and

a termination electrically positioned between the conductive return and the probe conductor, wherein the probe conductor is equidistant with the insulator along the contact surface.

8. The RF probe of claim 7, wherein the conductive return is a ground return.

9. The RF probe of claim 7, wherein the termination is a resistor.

10. (Amended) The RF probe of claim 9, wherein the probe conductor is formed within a coaxial conductor and the termination is approximately 50 ohms.

11. The RF probe of claim 7, wherein the termination is a semiconductor device.

12. The RF probe of claim 11, wherein the termination is a diode.

13. The RF probe of claim 7, wherein the insulator has at least a partial cross section that is substantially circular in a plane substantially perpendicular to the probe conductor.

14. The RF probe of claim 13, wherein the conductive return is a ground return.

15. The RF probe of claim 13, wherein the termination is a resistor.

16. (Amended) The RF probe of claim 15, wherein the termination is approximately 50 ohms.

17. The RF probe of claim 13, wherein the termination is a semiconductor device.

18. The RF probe of claim 17, wherein the termination is a diode.

19. (Amended) An RF probe, comprising:

a conductive return;

a probe conductor positioned within an insulator having a contact surface, the probe conductor being curved and the insulator having at least a partial cross section that is substantially circular in a plane substantially perpendicular to the probe conductor; and

a termination electrically positioned between the conductive return and the probe conductor, wherein the probe conductor is equidistant with the insulator along the contact surface.

Please insert the following new claim:

20. (Inserted) The RF probe of Claim 19, wherein the probe conductor is equidistant with an RF source along the contact surface.